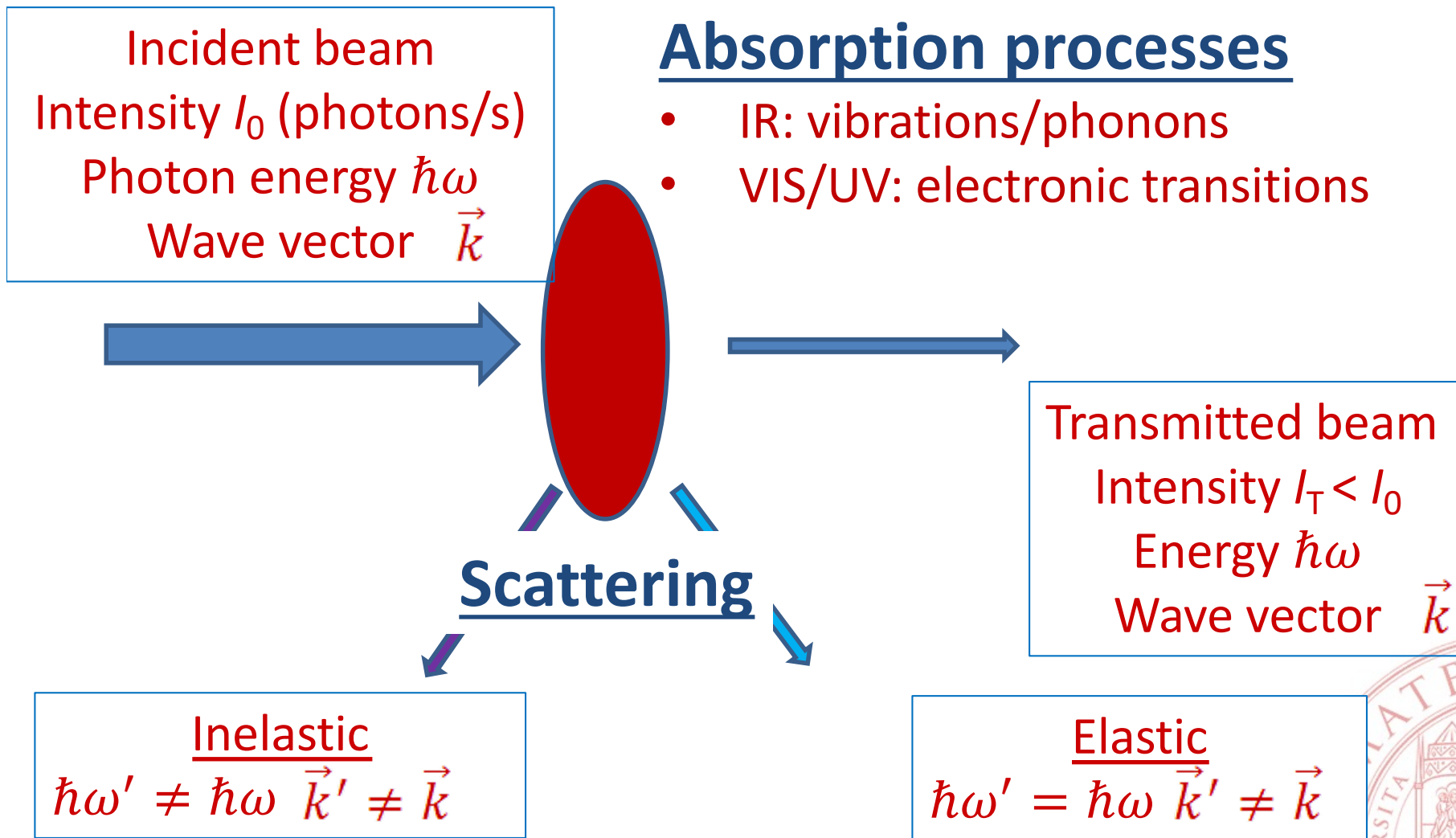
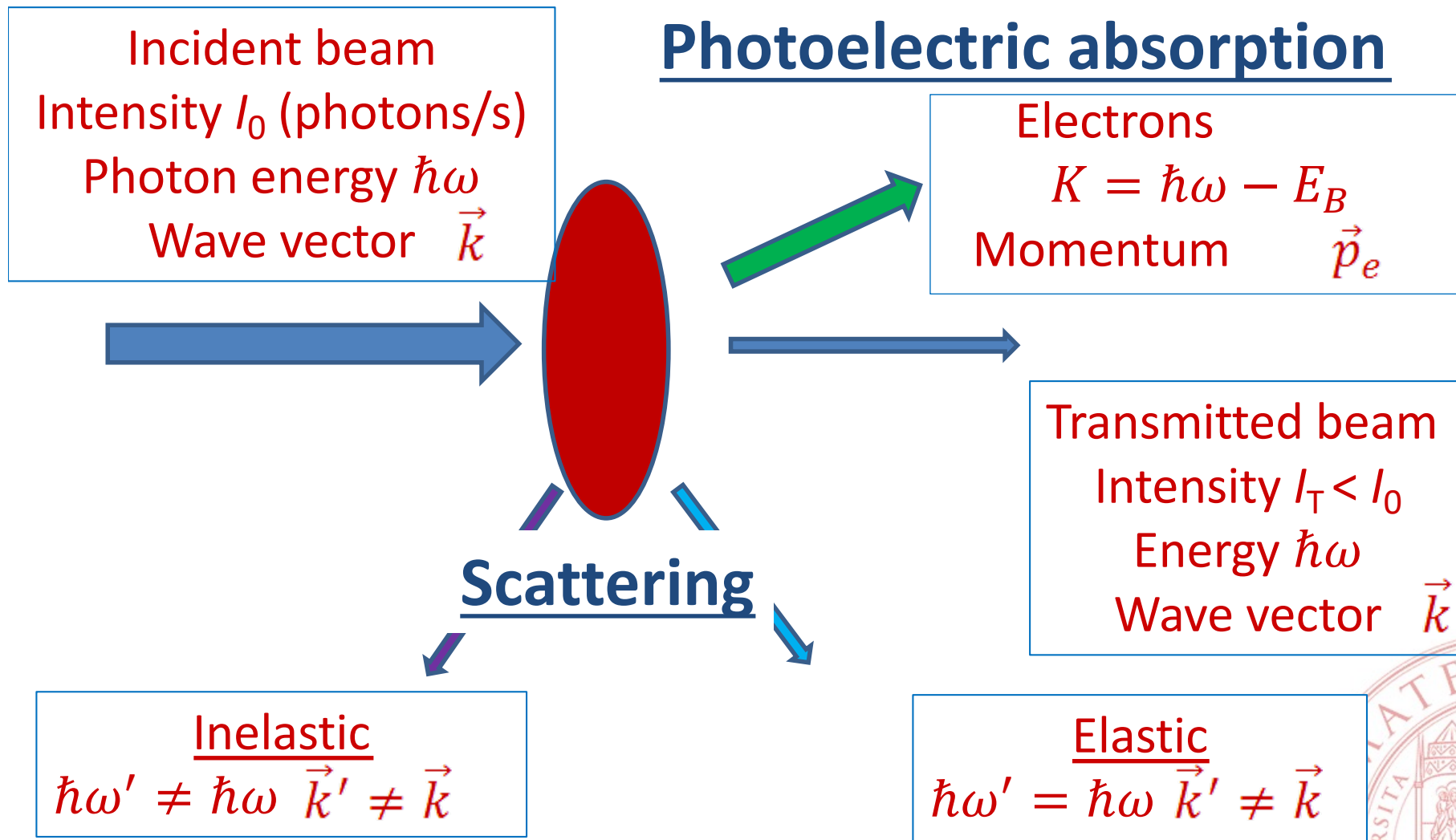


Interaction: atomic approach (IR to vis/UV)

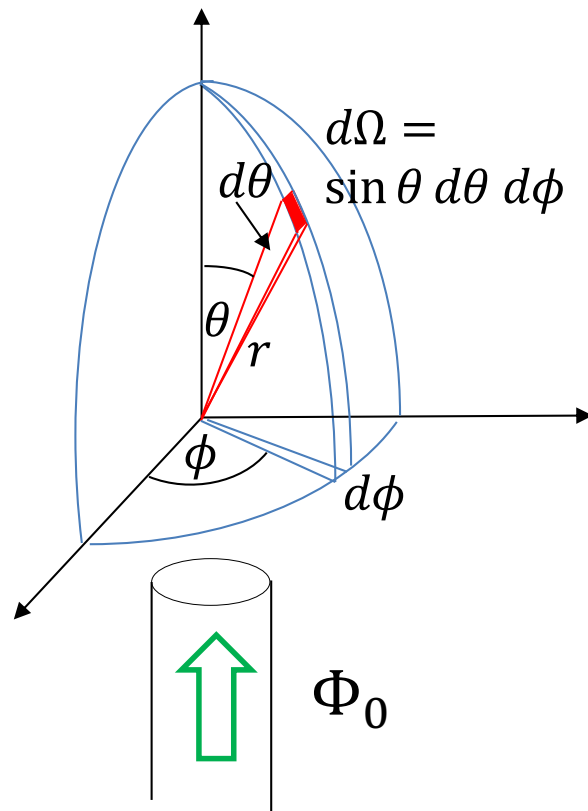


Interaction: atomic approach (UV to X-rays)



Cross section

- A single atom in the origin
- Interaction produces dN particles per unit time in the solid angle $d\Omega$



Impinging beam of
monochromatic
photons, flux Φ_0
 $\Phi_0 = \text{photons}/(\text{s cm}^2)$

$$dN = \Phi_0 d\sigma = \Phi_0 \left(\frac{d\sigma}{d\Omega} \right) d\Omega$$

$$\sigma = \int_{4\pi} \left(\frac{d\sigma}{d\Omega} \right) d\Omega$$

$$[\sigma] = \text{cm}^2$$

$$1 \text{ barn} = 10^{-24} \text{ cm}^2$$

Ge, $Z = 32$, $\hbar\omega = 10 \text{ keV}$

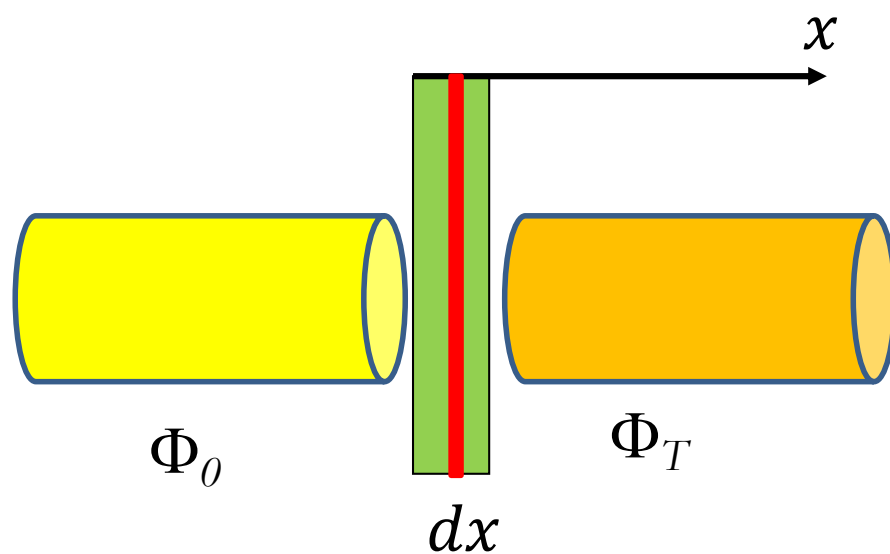
$$\sigma_{\text{photo}} = 4 \times 10^3 \text{ barn}$$

$$\sigma_{\text{el}} = 2 \times 10^2 \text{ barn}$$

$$\sigma_{\text{inel}} = 1 \times 10^1 \text{ barn}$$



Cross section & linear attenuation coefficient



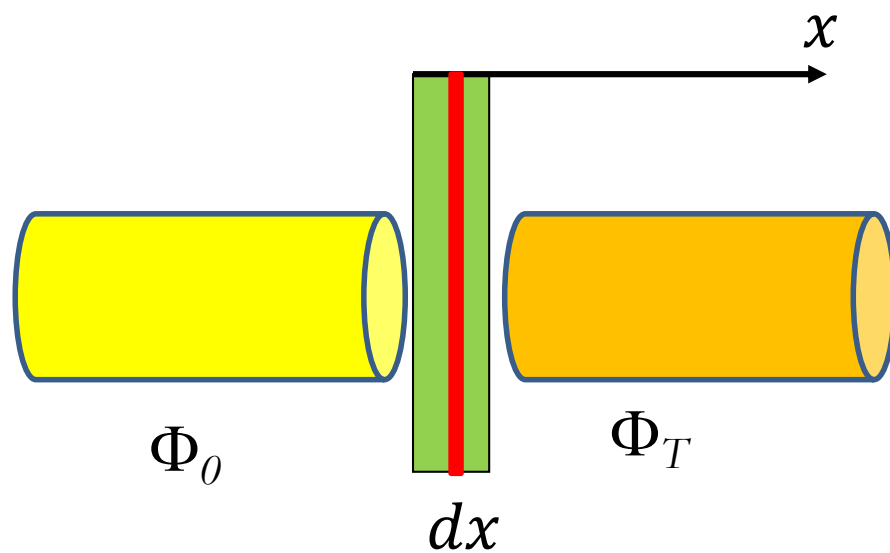
A homogeneous sample composed by identical atoms with density ρ (atoms/cm³)

- Single scattering approximation: the number of particles created by the interaction is \propto number of atoms involved
- The number of particles created by a slab of thickness dx at position x in the full solid angle is

$$\begin{aligned} dN &= \Phi \sigma dn \\ &= \Phi \sigma \rho A dx \\ &= I \sigma \rho dx \end{aligned}$$



Cross section & linear attenuation coefficient



A homogeneous sample composed by identical atoms with density ρ

- $dN = I \sigma \rho dx$
- Single particle approximation: an impinging photon can create only one particle. Therefore

$$dN = -dI$$

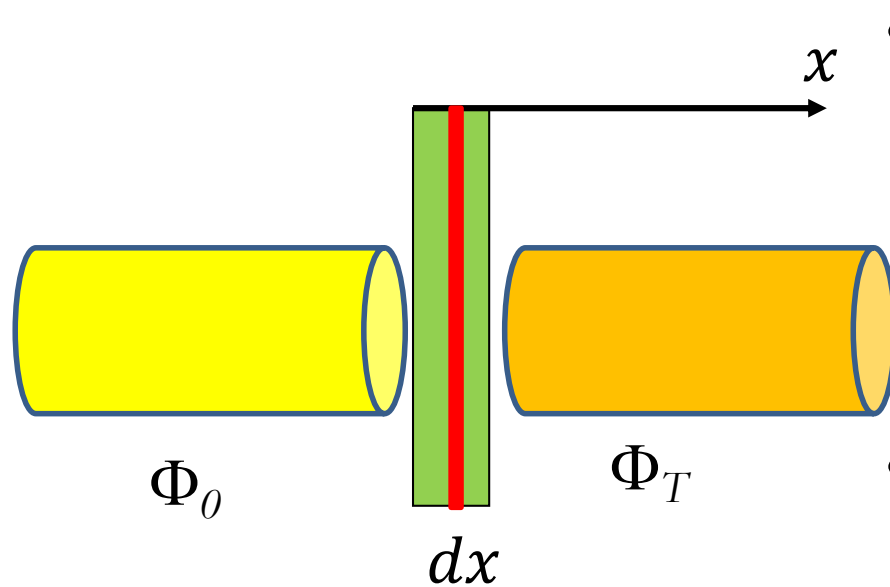
$$dI = -I \sigma \rho dx$$

- This is the same relation which defines the linear attenuation coefficient, thus

$$\mu = \sigma \rho$$



Cross section & linear attenuation coefficient



- If the sample is composed of different atoms with densities ρ_i and cross sections σ_i then

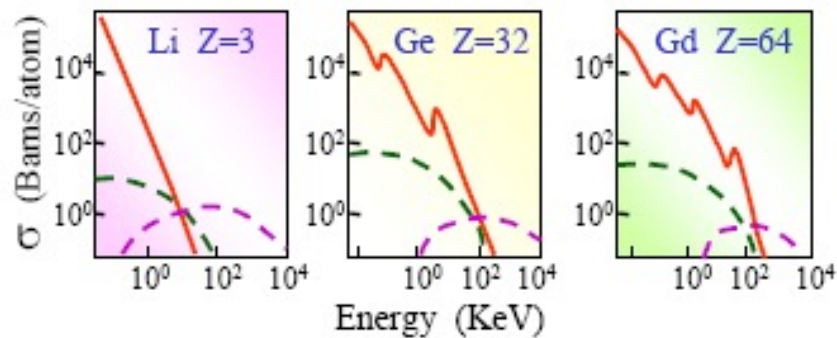
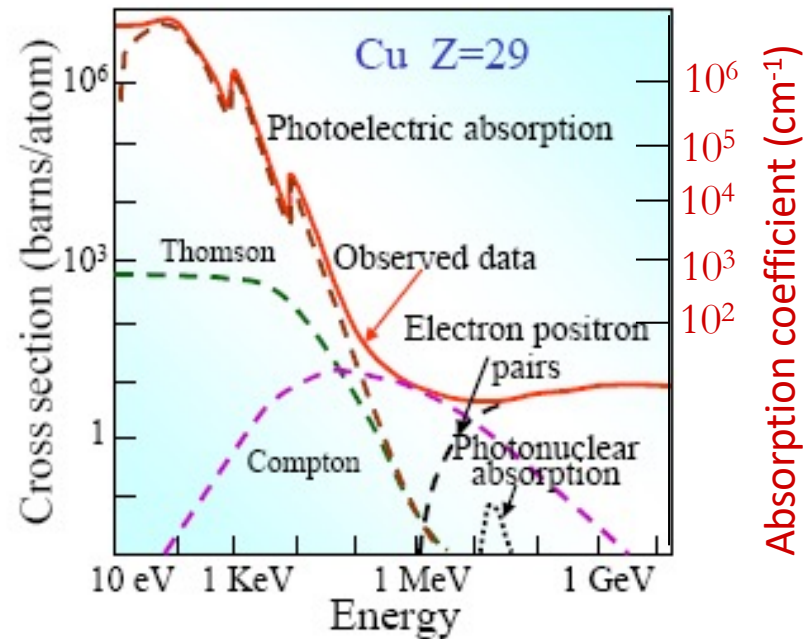
$$\mu = \sum_i \rho_i \sigma_i$$

- Cross sections are also expressed as mass attenuation coefficients, expressed as cm^2/g , so that

$$\begin{aligned} \mu(\text{cm}^{-1}) \\ = \rho(\text{g}/\text{cm}^3) \sigma(\text{cm}^2/\text{g}) \end{aligned}$$



Cross section of various processes



NB order of magnitude
 e.g. Cu @ 10 keV
 $\mu^{-1} \sim 10^{-5} \text{ cm} = 10 \mu\text{m}$



Elastic scattering from 1 free electron (Thomson)

- Thomson scattering = coherent scattering
- The scattered electric field is (linear polarization case)

$$E(\vec{r}, t) = -E_0 r_0 \left(\frac{e^{i(kr - \omega t)}}{r} \right) \sin \theta$$

$$r_0 = \frac{e^2}{4\pi\epsilon_0 mc^2} \cong 2.82 \times 10^{-15} \text{ m}$$

“Thomson scattering length”
or “classical electron radius”

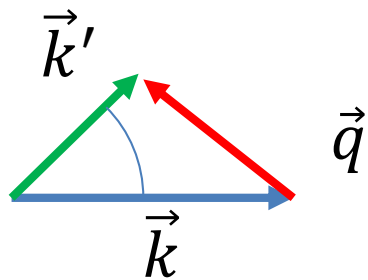
Angle between the polarization
vector and the
scattered wave vector



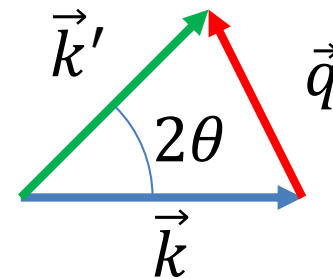
The exchanged wave vector

- $\vec{q} = \vec{k}' - \vec{k}$
- For elastic scattering $|\vec{k}'| = |\vec{k}| = k$ and

$$q = \frac{4\pi}{\lambda} \sin \theta$$



General case



Elastic scattering



Elastic scattering from 1 free electron (Thomson)

- The differential cross section is

$$\frac{d\sigma}{d\Omega} = r_0^2 (\hat{\varepsilon} \cdot \hat{\varepsilon}')^2$$

Polarization vectors of the
incident and scattered waves



Elastic scattering from 1 free electron (Thomson)

- The angle integrated (total) cross section is

$$\sigma = \frac{8\pi}{3} r_0^2$$

- NB: it is independent of energy



Elastic scattering from one atom

- For one atom

$$E(\vec{r}, t) = -E_0 r_0 \left(\frac{e^{i(kr - \omega t)}}{r} \right) f(Z, \theta) \sin \theta$$

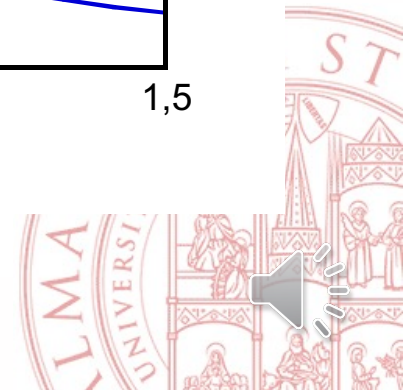
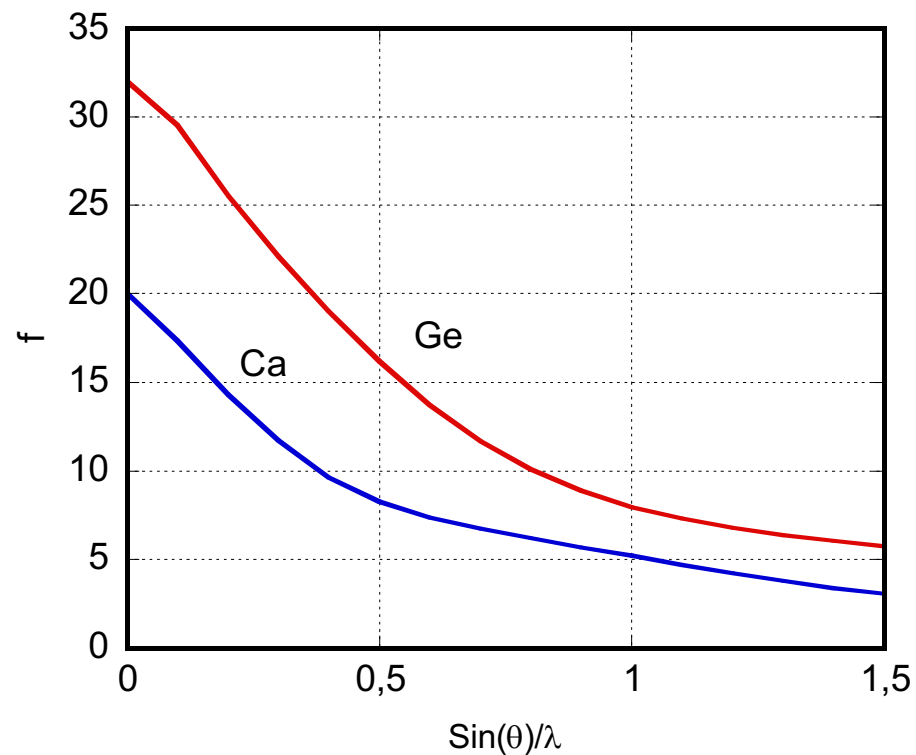
- $f(Z, \theta)$ is the «atomic form factor» or «scattering amplitude»; no physical dimensions



Elastic scattering from one atom

- The differential cross section $\frac{d\sigma}{d\Omega} = \frac{d\sigma_{electron}}{d\Omega} |f(Z, \theta)|^2$

- f depends quasi linearly on Z
- $f(\theta = 0) = Z$



Inelastic scattering

- The most common inelastic scattering mechanism for X-rays is the Compton effect (= “incoherent scattering”)

$$\Delta\lambda = 2\pi\lambda_c(1 - \cos\theta),$$

$$\lambda_c = \frac{\hbar}{mc} \cong 3.86 \times 10^{-13} \text{m},$$

Reduced Compton wavelength

$$a_0 = \frac{4\pi\epsilon_0\hbar^2}{me^2} \cong 0.53 \text{\AA}$$

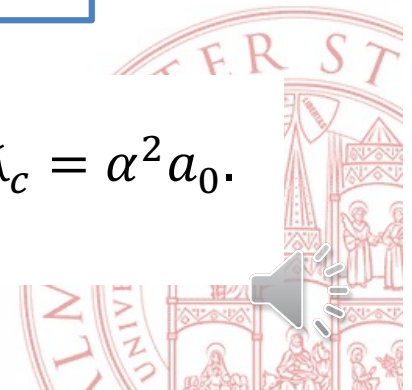
Radius of the Bohr 1st orbit for H

$$\alpha = \frac{e^2}{4\pi\epsilon_0\hbar c} \cong \frac{1}{137}$$

Fine structure constant

$$\lambda_c = \left(\frac{e^2}{4\pi\epsilon_0\hbar c} \right) \left(\frac{4\pi\epsilon_0\hbar^2}{me^2} \right) = \alpha a_0$$

$$r_0 = \left(\frac{e^2}{4\pi\epsilon_0\hbar c} \right) \left(\frac{\hbar}{mc} \right) = \alpha\lambda_c = \alpha^2 a_0.$$



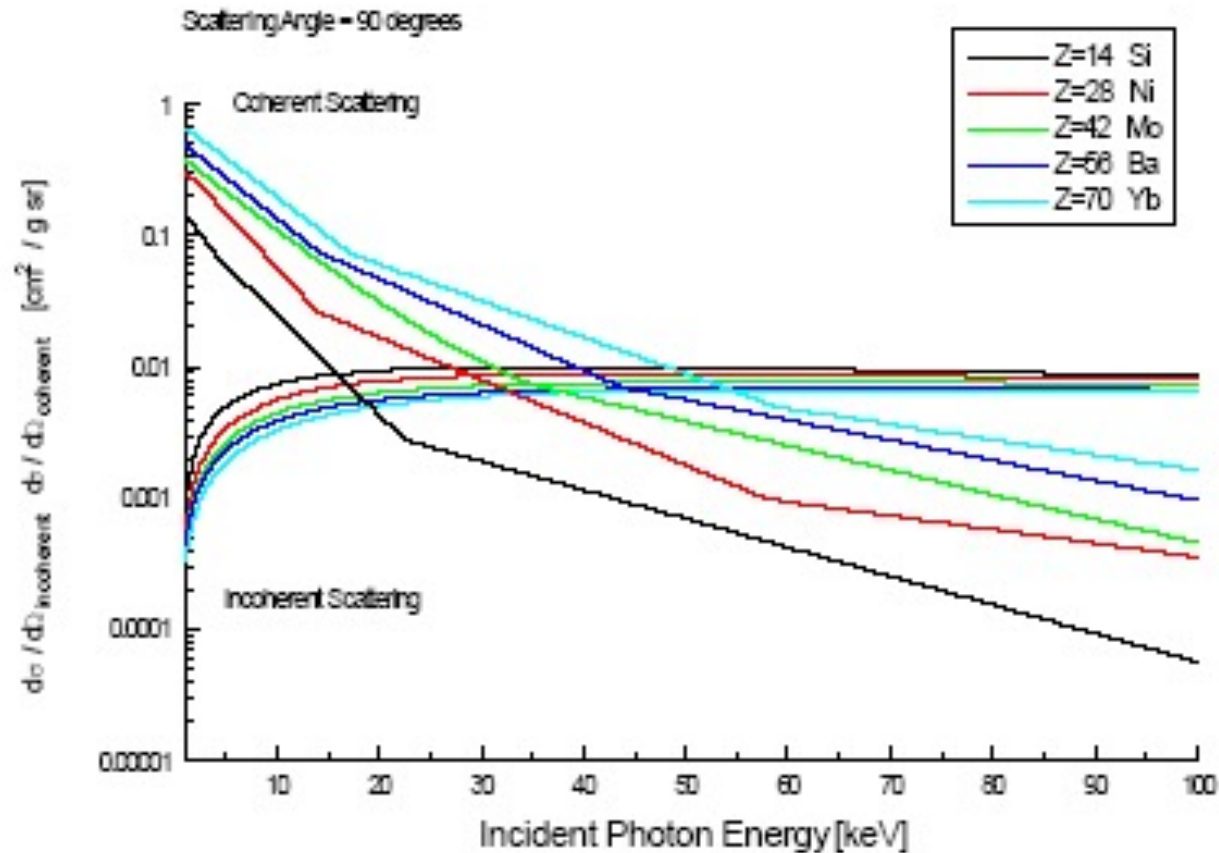
Compton cross section

- The Klein Nishina formula

$$\frac{d\sigma}{d\Omega} = r_0^2 \left(\frac{\omega'}{\omega} \right) \left| \hat{\varepsilon} \cdot \hat{\varepsilon}' + \frac{(\omega' - \omega)}{4\omega'\omega} \right|^2$$



Thomson and Compton scattering

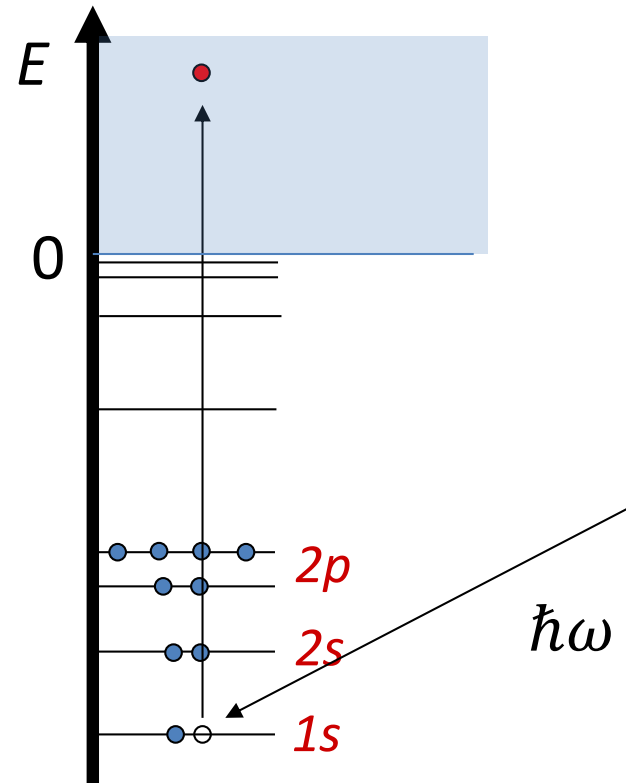


Elastic and inelastic scattering differential cross section for different elements as a function of the incident photon energy for a fixed scattering angle equal to 90 degrees. (Calculated using the data from reference



Photoelectric absorption

- A photon is absorbed and gives its energy to an electron.
- The electron makes a transition to
 - A bound state (excitation)
or
 - An unbound state (ionization): a photoelectron is created

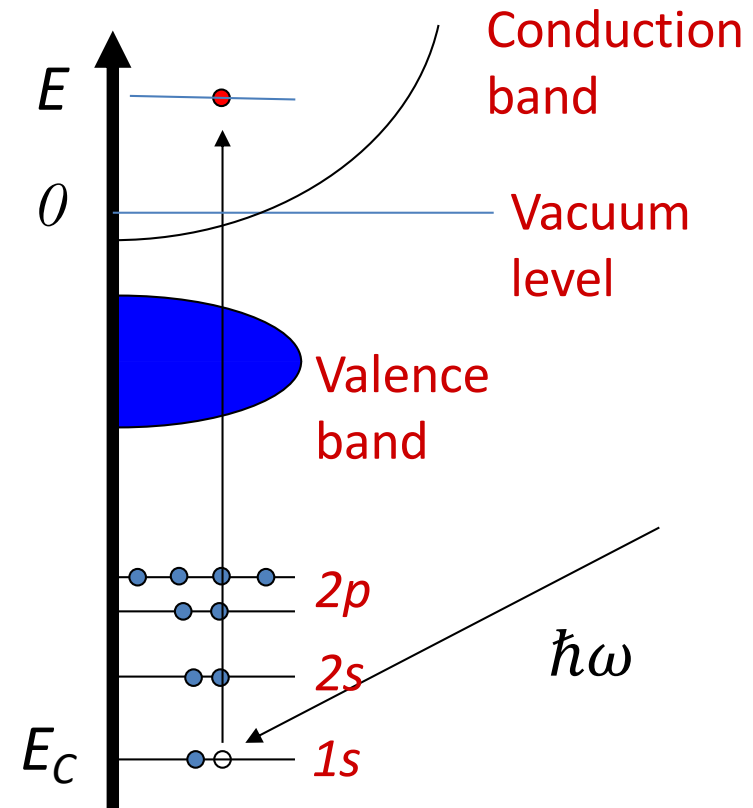


Energetics of photoelectric absorption
in an atom (ionization)



Photoelectric absorption in solids

- In solids valence electrons form bands
 - Insulators and semiconductors: valence and conduction bands
 - metals: conduction band
- The «vacuum level» is the least energy an electron can have to leave the solid (with K.E. = 0)
 - Often taken as reference level
- At sufficiently high energies the photoelectron can be considered «free»: it has only kinetic energy



Conservation of energy

- In the one electron approximation for a transition from a core level:

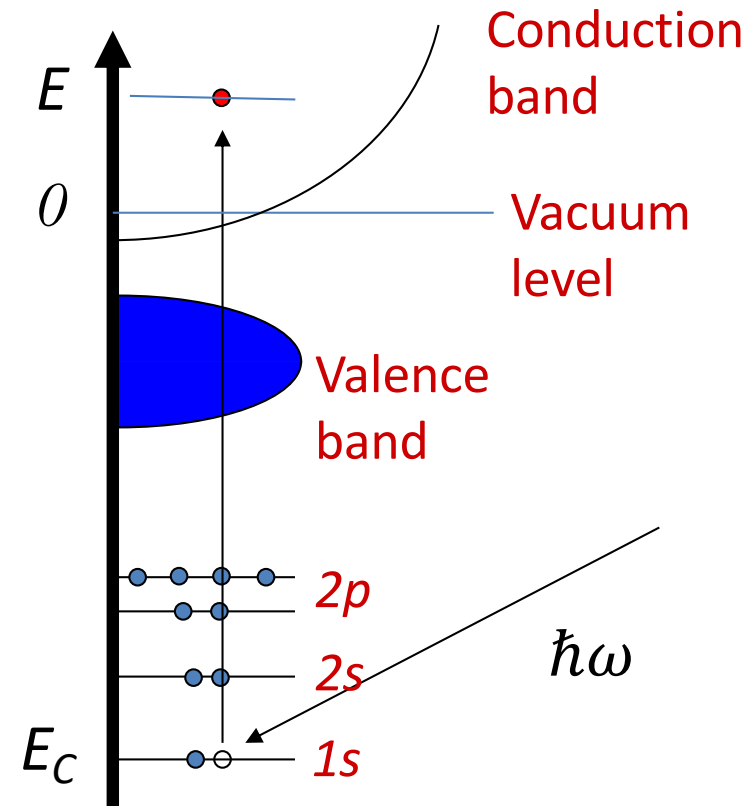
Initial state energy
= $\hbar\omega + E_C$ ($E_C < 0$)

Final state energy = K

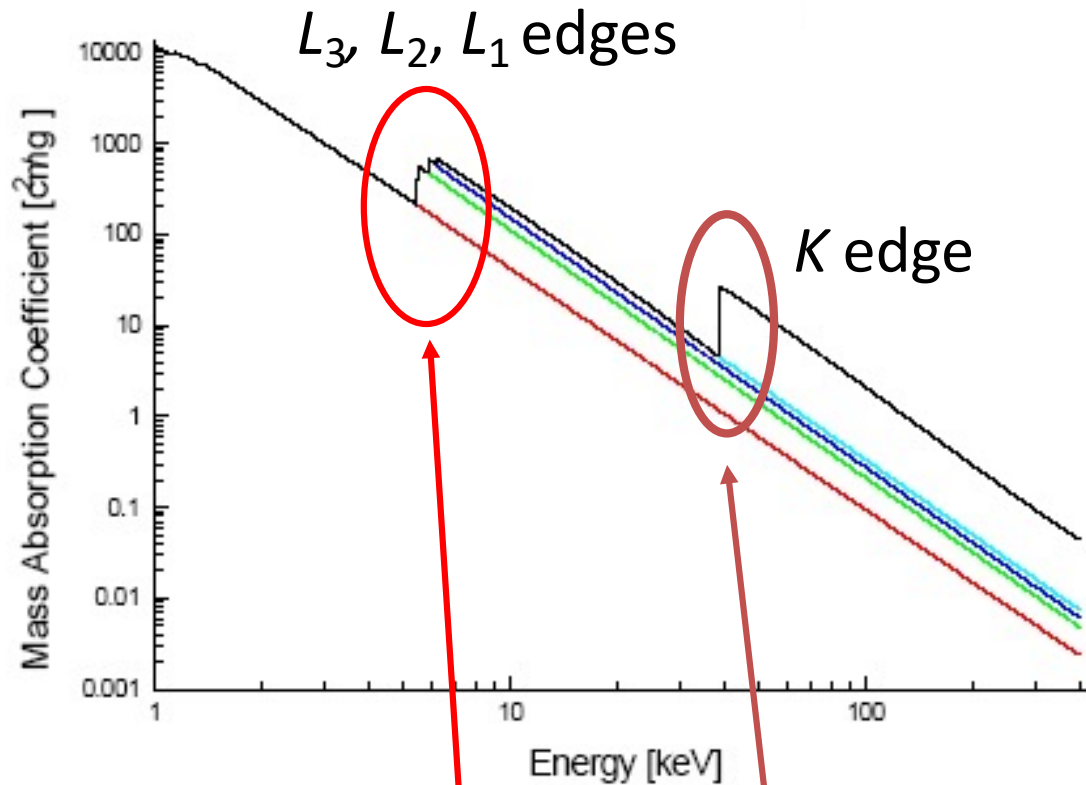
$$K = \hbar\omega + E_C$$

$E_C = -E_B$ (binding energy)

$$K = \hbar\omega - E_B$$

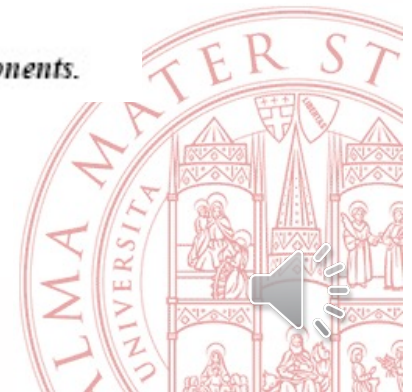


Absorption coefficient: energy dependence

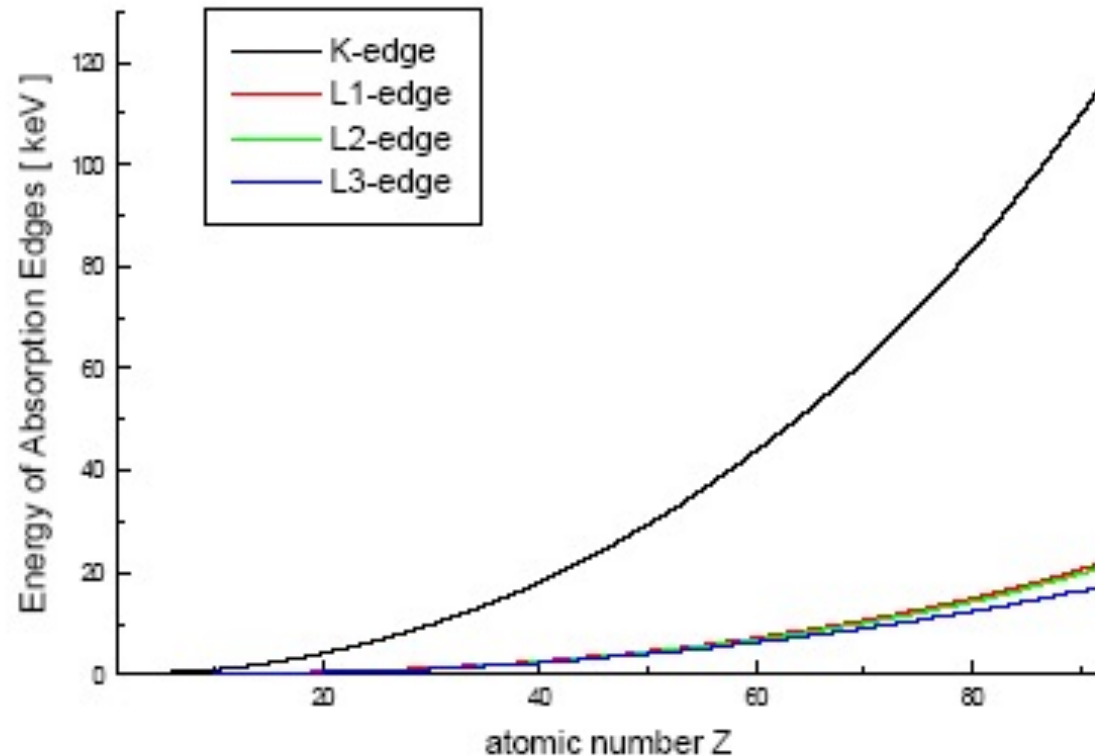


Mass absorption coefficient of Lanthanum ($Z=57$) versus energy of incident photons split in its components.

Absorption edges

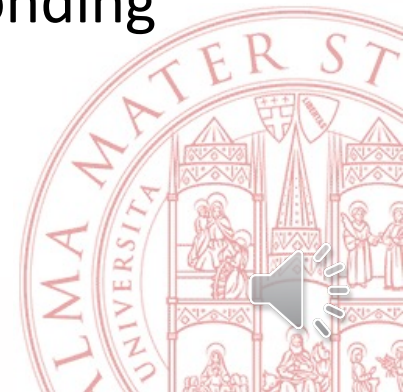


Z dependence of absorption edges

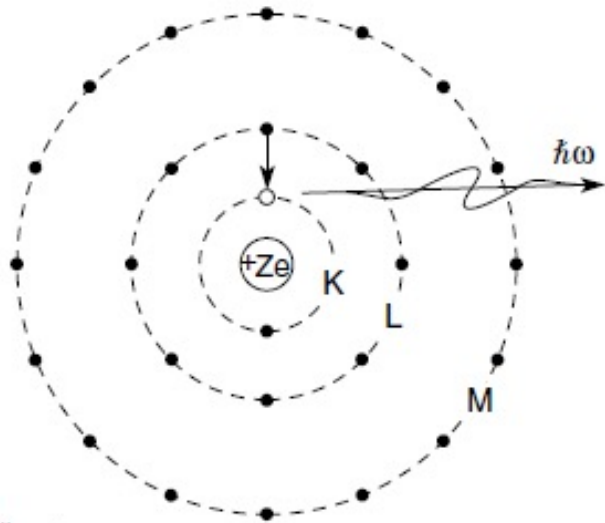


Energy of photoelectric absorption edges versus atomic number of the elements.

- The atomic number determines the energy of the absorption edge
- The observation of an edge at a given energy indicates the presence of the corresponding element

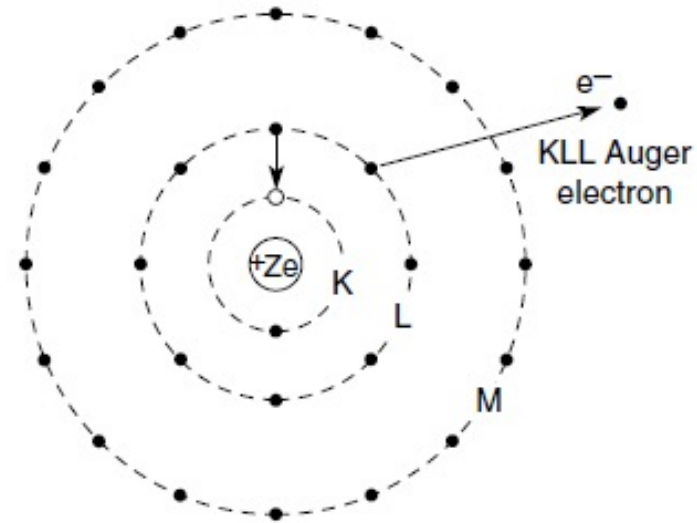


Photoelectric absorption: de-excitation



Emission of “characteristic” or
“fluorescence” X-rays,
also known as “emission lines”

$$\hbar\omega_f = E_L - E_K$$

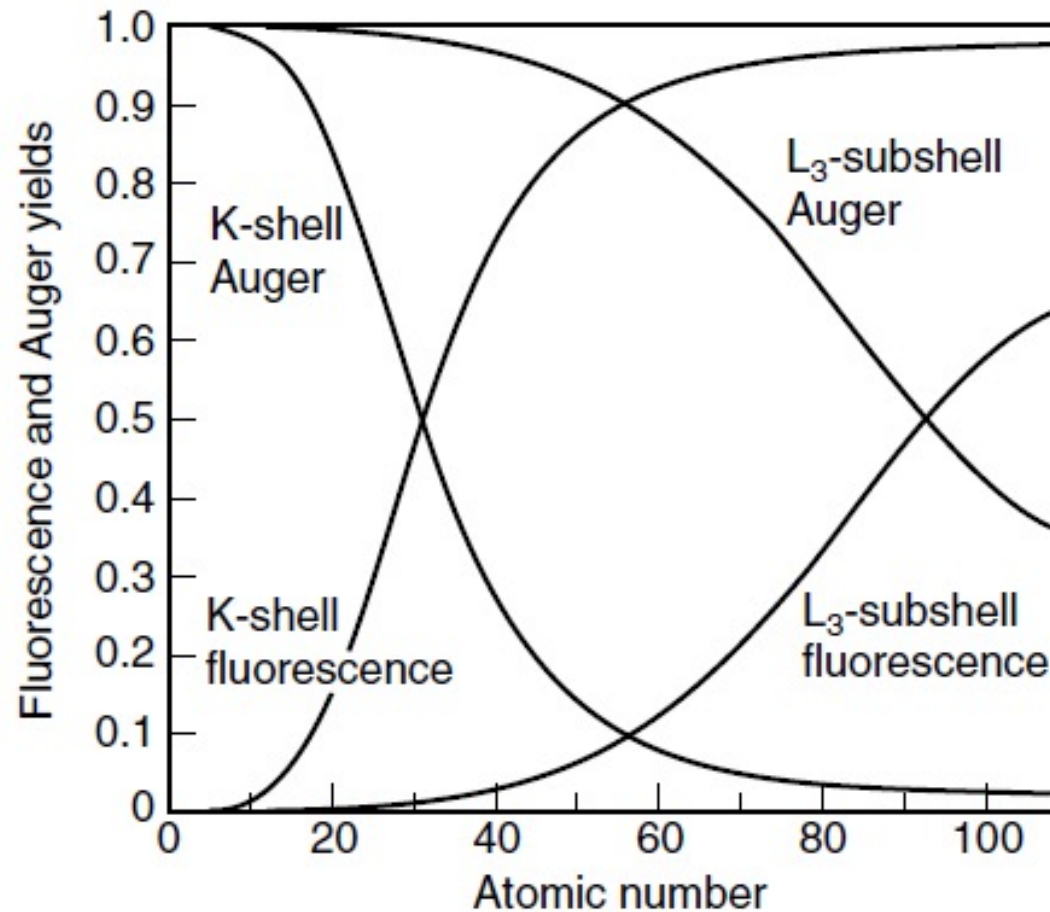


Emission of
“Auger” electrons”

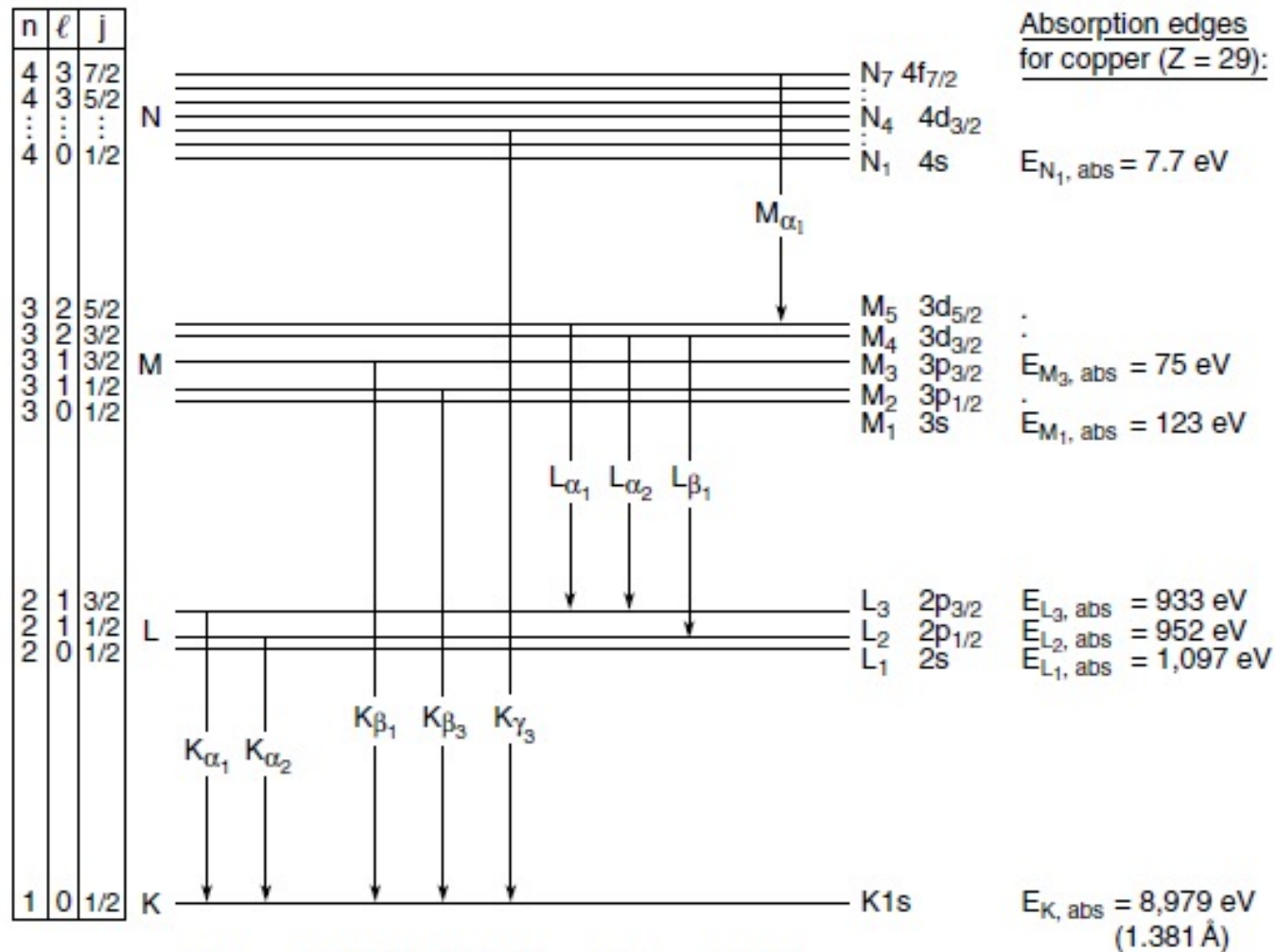
$$K_A = 2E_L - E_K$$



Probability for the two processes



Nomenclature for X-ray emission lines



Cu K_{α_1} = 8,048 eV (1.541 Å) Cu L_{α_1} = 930 eV
 Cu K_{α_2} = 8,028 eV (1.544 Å) Cu L_{α_2} = 930 eV
 Cu K_{β_1} = 8,905 eV Cu L_{β_1} = 950 eV



Energy of emission lines

- Energy depends on Z
- Measurement of the energy and intensity of x-ray emission lines is at the basis of many “analytical” techniques which measure the presence and concentration of elements in a sample

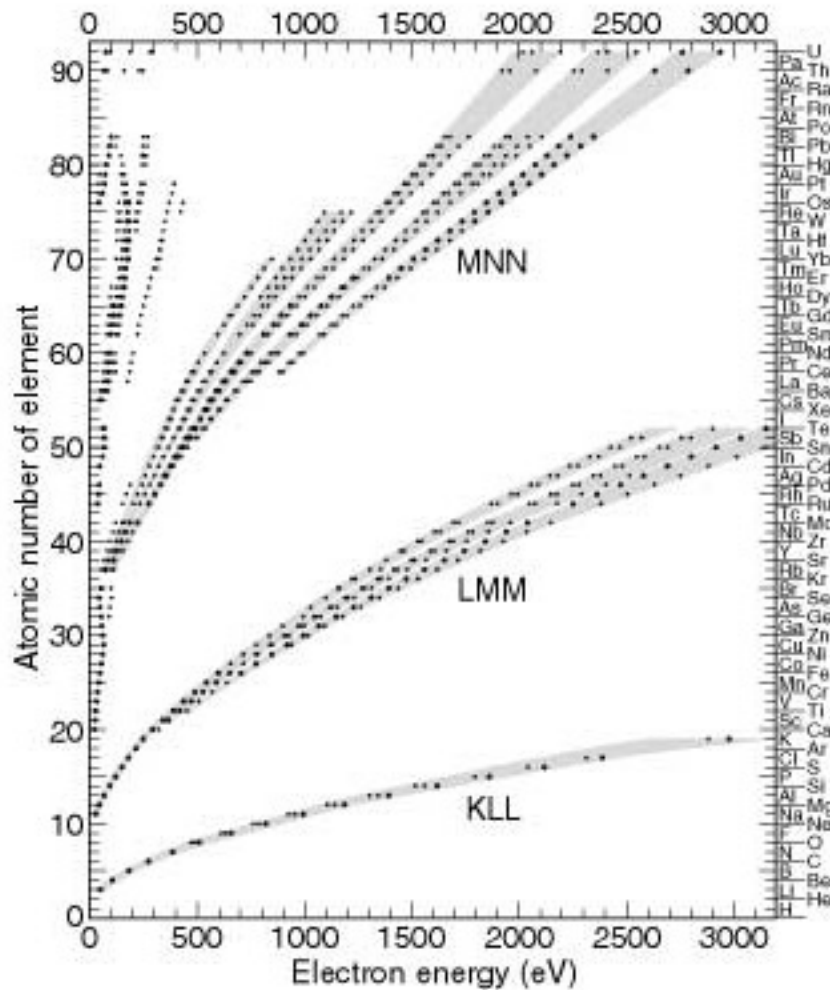
TABLE B.2. Photon energies, in electron volts, of principal K and L shell emission lines

| Element | K α_1 | K α_2 | K β_1 | L α_1 | L α_2 | L β_1 |
|---------|--------------|--------------|-------------|--------------|--------------|-------------|
| 3 Li | 54.3 | | | | | |
| 4 Be | 108.5 | | | | | |
| 5 B | 183.3 | | | | | |
| 6 C | 277 | | | | | |
| 7 N | 392.4 | | | | | |
| 8 O | 524.9 | | | | | |
| 9 F | 676.8 | | | | | |
| 10 Ne | 848.6 | 848.6 | | | | |
| 11 Na | 1,040.98 | 1,040.98 | 1,071.1 | | | |
| 12 Mg | 1,253.60 | 1,253.60 | 1,302.2 | | | |
| 13 Al | 1,486.70 | 1,486.27 | 1,557.45 | | | |
| 14 Si | 1,739.98 | 1,739.38 | 1,835.94 | | | |
| 15 P | 2,013.7 | 2,012.7 | 2,139.1 | | | |
| 16 S | 2,307.84 | 2,306.64 | 2,464.04 | | | |
| 17 Cl | 2,622.39 | 2,620.78 | 2,815.6 | | | |
| 18 Ar | 2,957.70 | 2,955.63 | 3,190.5 | | | |
| 19 K | 3,313.8 | 3,311.1 | 3,589.6 | | | |
| 20 Ca | 3,691.68 | 3,688.09 | 4,012.7 | 341.3 | 341.3 | 344.9 |
| 21 Sc | 4,090.6 | 4,086.1 | 4,460.5 | 395.4 | 395.4 | 399.6 |
| 22 Ti | 4,510.84 | 4,504.86 | 4,931.81 | 452.2 | 452.2 | 458.4 |
| 23 V | 4,952.20 | 4,944.64 | 5,427.29 | 511.3 | 511.3 | 519.2 |
| 24 Cr | 5,414.72 | 5,405.509 | 5,946.71 | 572.8 | 572.8 | 582.8 |
| 25 Mn | 5,898.75 | 5,887.65 | 6,490.45 | 637.4 | 637.4 | 648.8 |
| 26 Fe | 6,403.84 | 6,390.84 | 7,057.98 | 705.0 | 705.0 | 718.5 |
| 27 Co | 6,930.32 | 6,915.30 | 7,649.43 | 776.2 | 776.2 | 791.4 |
| 28 Ni | 7,478.15 | 7,460.89 | 8,264.66 | 851.5 | 851.5 | 868.8 |
| 29 Cu | 8,047.78 | 8,027.83 | 8,905.29 | 929.7 | 929.7 | 949.8 |
| 30 Zn | 8,638.86 | 8,615.78 | 9,572.0 | 1,011.7 | 1,011.7 | 1,034.7 |



Auger electrons

- Nomenclature
 - (Hole)(1st e⁻)(2nd e⁻)
- The energy depends on Z
- Measurement of the energy and intensity of Auger electrons = “Auger Electron Spectroscopy”, an analytic technique which measures the presence and concentration of elements on the surface of a sample



Relationship between two approaches

- Two approaches to describe the interaction between x-rays and matter
 - «Macroscopic»: by means of the dielectric function which describes the overall response
 - «Microscopic»: by means of interactions between photons and atoms
- What is the relation between these approaches?
- It is possible to derive a simple relation between the index of refraction and the atomic form factor



Relation between n and f

- For a sample composed of identical atoms with form factor f and density ρ

$$n(\omega) - 1 = - \frac{2\pi r_0 \rho f(\omega, q = 0)}{k^2}$$

- $n(\omega)$ has a real and imaginary part: also $f(\omega)$!
 - Real part: dispersion
 - Imaginary part: attenuation



«Anomalous" corrections to the form factor

- It is common to separate the dependence on \vec{q} and ω : $f(\vec{q}, \omega) = f^0(\vec{q}) + f'(\omega) - if''(\omega)$
 - $f^0(\vec{q})$: atomic scattering far from resonance frequencies / absorption edges
 - $f'(\omega)$: correction to dispersive part, important near resonance frequencies
 - $f''(\omega)$: correction to attenuation part, important near resonance frequencies



The total cross section

- The total cross section determines the attenuation, $\sigma_T(\omega) = \frac{\mu(\omega)}{\rho} = \frac{2\omega n_2(\omega)}{c\rho}$
- Since $n_2(\omega) = \frac{2\pi r_0 \rho f''(\omega, q=0)}{k^2}$

$$\sigma_T(\omega) = \frac{4\pi r_0}{k} f''(\omega, q = 0)$$

one form of the «optical theorem», which links the total cross section to the imaginary part of the forward scattering amplitude

